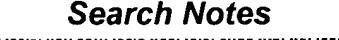


Search Notes 	Application/Control No.	Applicant(s)/Patent under Reexamination
	10/728,531	LAI ET AL.
	Examiner	Art Unit
	Tae H. Yoon	1714

INTERFERENCE SEARCHED			
Class	Subclass	Date	Examiner